

### **Description**

The AP2305MI uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a

Battery protection or in other Switching application.



 $V_{DS} = -20V I_{D} = -4.9A$ 

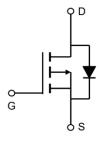
 $R_{DS(ON)}$  < 38m $\Omega$  @  $V_{GS}$ =-4.5V

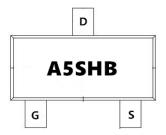
## **Application**

Battery protection

Load switch

Uninterruptible power supply







**Package Marking and Ordering Information** 

Product ID	Pack	Marking	Qty(PCS)
AP2305MI	SOT-23-3L	A5SHB.	3000

### Absolute Maximum Ratings (T<sub>c</sub>=25 ℃ unless otherwise noted)

Symbol	Parameter	Rating	Units	
V <sub>DS</sub>	Drain-Source Voltage	Drain-Source Voltage -20		
V <sub>GS</sub>	Gate-Source Voltage	Gate-Source Voltage ±12		
I <sub>D</sub> @T <sub>A</sub> =25℃	Continuous Drain Current, V <sub>GS</sub> @ -4.5V <sup>1</sup>	-4.9	Α	
I <sub>D</sub> @T <sub>A</sub> =70°C	Continuous Drain Current, V <sub>GS</sub> @ -4.5V <sup>1</sup>	-3.9	Α	
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	-14	Α	
P <sub>D</sub> @T <sub>A</sub> =25℃	Total Power Dissipation <sup>3</sup>	1.31	W	
P <sub>D</sub> @T <sub>A</sub> =70℃	Total Power Dissipation <sup>3</sup>	0.84	W	
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	$^{\circ}$	
TJ	Operating Junction Temperature Range	-55 to 150	$^{\circ}$	
R <sub>θ</sub> JA	Thermal Resistance Junction-Ambient <sup>1</sup>	120	°C/W	
R <sub>θ</sub> JA	Thermal Resistance Junction-Ambient ¹ (t ≤10s)	95	°C/W	





## Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS}$ =0 $V$ , $I_{D}$ =-250 $u$ A	-20			V
△BVDSS/△TJ	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25℃ , I <sub>D</sub> =-1mA		-0.014	-	V/°C
		$V_{GS}$ =-4.5 $V$ , $I_{D}$ =-4.9 $A$	-	32	38	
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}$ =-2.5V , $I_D$ =-3.4A		45	55	$m\Omega$
		$V_{GS}$ =-1.8 $V$ , $I_{D}$ =-2 $A$	I	65	85	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}$ , $I_D=-250uA$	-0.4		-1.0	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	VGS-VDS , ID250UA		3.95	-	mV/℃
I <sub>DSS</sub>	Drain-Source Leakage Current	$V_{DS}$ =-16V , $V_{GS}$ =0V , $T_{J}$ =25 $^{\circ}$ C			-1	uA
		$V_{DS}$ =-16V , $V_{GS}$ =0V , $T_{J}$ =55 $^{\circ}$ C			-5	uA
Igss	Gate-Source Leakage Current	V <sub>GS</sub> =±12V , V <sub>DS</sub> =0V			±100	nA
gfs	Forward Transconductance	$V_{DS}$ =-5V , $I_{D}$ =-3A		12.8		S
$Q_g$	Total Gate Charge (-4.5V)			10.2	14.3	
Q <sub>gs</sub>	Gate-Source Charge	$V_{DS}$ =-15V , $V_{GS}$ =-4.5V , $I_{D}$ =-3A		1.89	2.6	nC
$Q_{gd}$	Gate-Drain Charge			3.1	4.3	
T <sub>d(on)</sub>	Turn-On Delay Time			5.6	11.2	
Tr	Rise Time	$V_{DD}$ =-10V , $V_{GS}$ =-4.5V ,		40.8	73	
T <sub>d(off)</sub>	Turn-Off Delay Time	$R_G=3.3$ , $I_D=-3A$		33.6	67	ns
T <sub>f</sub>	Fall Time			18	36	
Ciss	Input Capacitance			857	1200	
Coss	Output Capacitance	$V_{DS}$ =-15V , $V_{GS}$ =0V , f=1MHz		114	160	F
Crss	Reverse Transfer Capacitance			108	151	pF
Is	Continuous Source Current <sup>1,4</sup>	V V 0V E 0 1			-4.9	Α
Іѕм	Pulsed Source Current <sup>2,4</sup>	$V_G=V_D=0V$ , Force Current			-14	Α
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25℃			-1	V
t <sub>rr</sub>	Reverse Recovery Time	IF=-3A , di/dt=100A/μs ,		21.8		nS
Qrr	Reverse Recovery Charge	TJ=25°C		6.9		nC

#### Note:

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2  $\,$  The data tested by pulsed , pulse width  $\triangle$  300us , duty cycle  $\triangle$  2%
- $3 {\,{}^{^{}}_{^{}}}$  The power dissipation is limited by  $150 {\,{}^{^{}}\!\!}{}^{^{^{}}}$  junction temperature
- $4\sqrt{100}$  The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



### **Typical Characteristics**

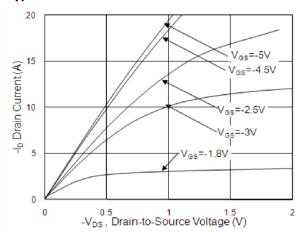


Fig.1 Typical Output Characteristics

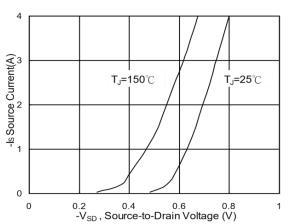


Fig.3 Forward Characteristics of Reverse

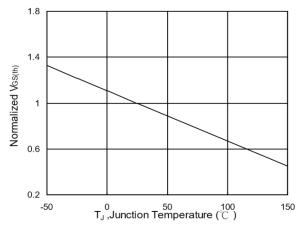


Fig.5 Normalized  $V_{\text{GS(th)}}$  vs.  $T_{\text{J}}$ 

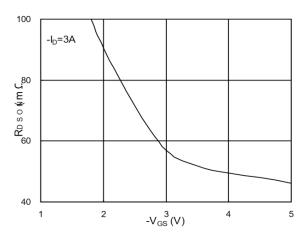


Fig.2 On-Resistance vs. G-S Voltage

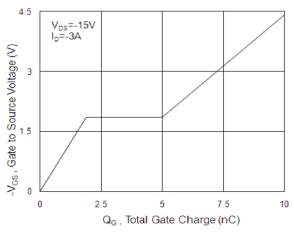


Fig.4 Gate-charge Characteristics

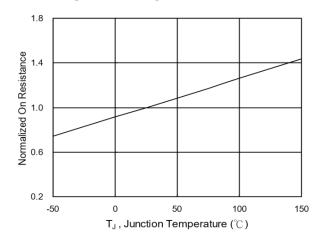
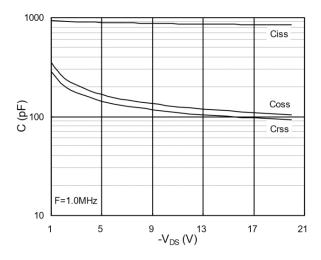


Fig.6 Normalized Roson vs. TJ





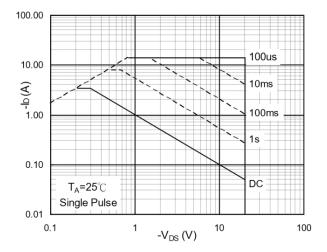


Fig.7 Capacitance

Fig.8 Safe Operating Area

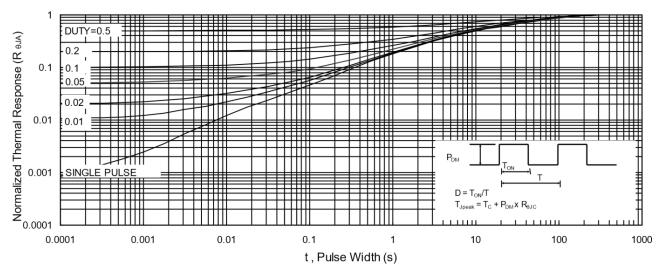
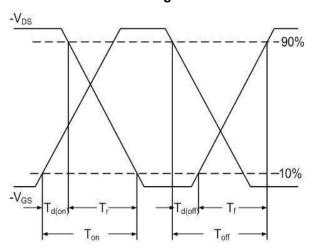


Fig.9 Normalized Maximum Transient Thermal Impedance



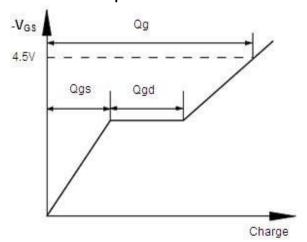


Fig.10 Switching Time Waveform

Fig.11 Gate Charge Waveform



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Edition	Date	Change
Rve1.0	2020/4/31	Initial release

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